

**Search Notes**

Application/Control No.

10/644,755

Examiner

Anthony Weier

Applicant(s)/Patent under  
Reexamination

LORTZ ET AL.

Art Unit

1761

**SEARCHED**

Class	Subclass	Date	Examiner
updated	previous search	6/20/2007	AW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR